

## FCC 47 CFR § 2.1093 IEEE Std 1528-2013

## SAR EVALUATION REPORT (Part 0 : SAR CHARACTERIZATION)

FOR

## WCDMA/LTE/5G NR Laptop + BT/BLE, DTS/UNII a/b/g/n/ac/ax

MODEL NUMBER: NP545XLA

## FCC ID: A3LNP545XLA1

REPORT NUMBER: 4790047184-S1V1

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**Testing Laboratory** 

TL-637

## **Revision History**

Rev.	Date	Revisions	Revised By
V1	9/2/2021	Initial Issue	

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# 1. Attestation of SAR Characterization

Applicant Name	SAMSUNG ELECTRONICS CO., LTD.
FCC ID	A3LNP545XLA1
Model Number	NP545XLA
Applicable Standards	FCC 47 CFR § 2.1093
	IEEE Std 1528-2013
	Published RF exposure KDB procedures
Report type	Part.0 : SAR Characterization
Date Tested	Reference model : 4/21/2021 to 6/14/2021
	Variant model : 8/10/2021 to 9/2/2021
Part 0 Purpose	Part 0 is the procedures for determining <i>P</i> <sub>Limit</sub> for 3G/4G/5G NR sub6 to satisfy <i>SAR_design_target</i> in order to FCC limit's requirement.

UL Korea, Ltd. tested the above equipment in accordance with the requirements set forth in the above standards. All indications of Pass/Fail in this report are opinions expressed by UL Korea, Ltd. based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

**Note:** The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL Korea, Ltd. and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL Korea, Ltd. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by IAS, any agency of the Federal Government, or any agency of any government.

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# 2. Introduction

The equipment under test (EUT) is SAMSUNG Tablet (FCC ID : A3LNP545XLA1), it contains the Qualcomm modems supporting 3G/4G/5G NR technologies. These modems are enable with Qualcomm Smart Transmit feature to control and manage transmitting power in real time and to ensure at all times the time-averaged RF exposure is in compliance with FCC requirement.

This purpose of the part 0 report is to determine SAR char is derived from SAR test measurements and conducted power measurements to determine *PLimit* for each technology/band. The *PLimit* represents the maximum time-averaged power level for the corresponding radio/antenna configuration.

# 3. Introduction Of Test Data Referencing

This report referenced from the FCC ID: A3LNP545XLA SAR (FCC 47 CFR § 2.1093, IEEE 1528-2013).

And the applicant takes full responsibility that the test data as referenced in this report represent compliance for this FCC ID.

Detail of Test Data Referencing refer to Section 1.3 to 1.4 in Part.1 report.

# 4. Facilities and Accreditation

The test sites and measurement facilities used to collect data are located at

Suwon
SAR 1 Room
SAR 2 Room
SAR 3 Room
SAR 4 Room
SAR 5 Room

UL Korea, Ltd. is accredited by IAS, Laboratory Code TL-637.

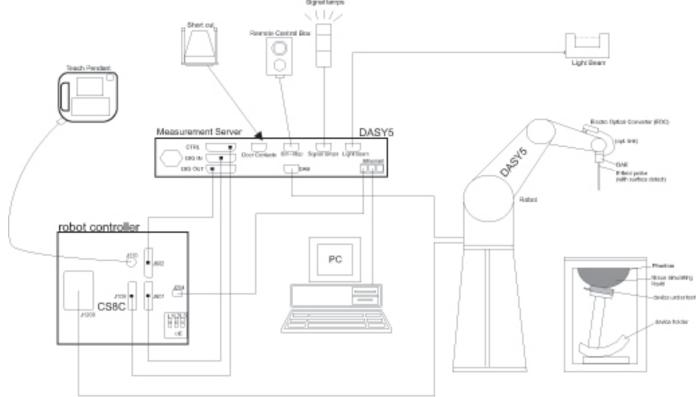
The full scope of accreditation can be viewed at <u>https://www.iasonline.org/wp-content/uploads/2017/05/TL-637 - cert-New.pdf.</u>

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# 5. SAR Measurement System & Test Equipment

## 5.1. SAR Measurement System

The DASY5 system used for performing compliance tests consists of the following items:



- A standard high precision 6-axis robot with controller, teach pendant and software. An arm extension for accommodating the data acquisition electronics (DAE).
- An isotropic Field probe optimized and calibrated for the targeted measurement.
- A data acquisition electronics (DAE) which performs the signal amplification, signal multiplexing, ADconversion, offset measurements, mechanical surface detection, collision detection, etc. The unit is battery powered with standard or rechargeable batteries. The signal is optically transmitted to the EOC.
- The Electro-optical converter (EOC) performs the conversion from optical to electrical signals for the digital communication to the DAE. To use optical surface detection, a special version of the EOC is required. The EOC signal is transmitted to the measurement server.
- The function of the measurement server is to perform the time critical tasks such as signal filtering, control of the robot operation and fast movement interrupts.
- The Light Beam used is for probe alignment. This improves the (absolute) accuracy of the probe positioning.
- A computer running WinXP or Win7 and the DASY5 software.
- Remote control and teach pendant as well as additional circuitry for robot safety such as warning lamps, etc.
- The phantom, the device holder and other accessories according to the targeted measurement.

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## 5.2. SAR Scan Procedures

#### **Step 1: Power Reference Measurement**

The Power Reference Measurement and Power Drift Measurements are for monitoring the power drift of the device under test in the batch process. The minimum distance of probe sensors to surface determines the closest measurement point to phantom surface. The minimum distance of probe sensors to surface is 2.1 mm. This distance cannot be smaller than the distance of sensor calibration points to probe tip as defined in the probe properties.

### Step 2: Area Scan

The Area Scan is used as a fast scan in two dimensions to find the area of high field values, before doing a fine measurement around the hot spot. The sophisticated interpolation routines implemented in DASY software can find the maximum locations even in relatively coarse grids. When an Area Scan has measured all reachable points, it computes the field maximal found in the scanned area, within a range of the global maximum. The range (in dB) is specified in the standards for compliance testing. For example, a 2 dB range is required in IEEE Standard 1528 and IEC 62209 standards, whereby 3 dB is a requirement when compliance is assessed in accordance with the ARIB standard (Japan). If only one Zoom Scan follows the Area Scan, then only the absolute maximum will be taken as reference. For cases where multiple maximums are detected, the number of Zoom Scans has to be increased accordingly.

4	Area Scan Parameters extracted from KDB 865664 D01	SAR Measurement 100 MH	z to 6 GHz

	$\leq$ 3 GHz	> 3 GHz
Maximum distance from closest measurement point (geometric center of probe sensors) to phantom surface	$5 \pm 1 \text{ mm}$	$\frac{1}{2} \cdot \delta \cdot \ln(2) \pm 0.5 \text{ mm}$
Maximum probe angle from probe axis to phantom surface normal at the measurement location	$30^{\circ}\pm1^{\circ}$	$20^\circ\pm1^\circ$
	$\leq$ 2 GHz: $\leq$ 15 mm 2 - 3 GHz: $\leq$ 12 mm	$3 - 4 \text{ GHz} \le 12 \text{ mm}$ $4 - 6 \text{ GHz} \le 10 \text{ mm}$
Maximum area scan spatial resolution: $\Delta x_{Area}$ , $\Delta y_{Area}$	When the x or y dimension of the test device, in the measurement plane orientation, is smaller than the above, the measurement resolution must be $\leq$ the corresponding x or y dimension of the test device with at least one measurement point on the test device.	

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#### Step 3: Zoom Scan

Zoom Scans are used to assess the peak spatial SAR values within a cubic averaging volume containing 1 g and 10 g of simulated tissue. The Zoom Scan measures points (refer to table below) within a cube whose base faces are centered on the maxima found in a preceding area scan job within the same procedure. When the measurement is done, the Zoom Scan evaluates the averaged SAR for 1 g and 10 g and displays these values next to the job's label.

		$\leq$ 3 GHz	> 3 GHz	
Maximum zoom scan spatial resolution $\Delta x_{Zoom}$ , $\Delta y_{Zoom}$			$\leq 2 \text{ GHz}: \leq 8 \text{ mm}$ 2 - 3 GHz: $\leq 5 \text{ mm}^*$	3 – 4 GHz: ≤ 5 mm <sup>*</sup> 4 – 6 GHz: ≤ 4 mm <sup>*</sup>
	uniform grid: $\Delta z_{Zoom}(n)$		$\leq$ 5 mm	$3 - 4$ GHz: $\leq 4$ mm $4 - 5$ GHz: $\leq 3$ mm $5 - 6$ GHz: $\leq 2$ mm
Maximum zoom scan spatial resolution, normal to phantom surface	graded grid	$\Delta z_{Z_{com}}(1)$ : between 1 <sup>st</sup> two points closest to phantom surface	$\leq$ 4 mm	3 – 4 GHz: ≤ 3 mm 4 – 5 GHz: ≤ 2.5 mm 5 – 6 GHz: ≤ 2 mm
		Δz <sub>Zoom</sub> (n>1): between subsequent points	$\leq 1.5 \cdot \Delta z_{Zoom}(n-1)$	
Minimum zoom scan volume x, y, z		≥ 30 mm	$\begin{array}{l} 3-4 \ \mathrm{GHz} : \geq 28 \ \mathrm{mm} \\ 4-5 \ \mathrm{GHz} : \geq 25 \ \mathrm{mm} \\ 5-6 \ \mathrm{GHz} : \geq 22 \ \mathrm{mm} \end{array}$	
Note: ô is the penetration depth of a plane-wave at normal incidence to the tissue medium; see draft standard IEEE P1528-2011 for details.				

When zoom scan is required and the <u>reported</u> SAR from the *area scan based 1-g SAR estimation* procedures of KDB 447498 is  $\leq$  1.4 W/kg,  $\leq$  8 mm,  $\leq$  7 mm and  $\leq$  5 mm zoom scan resolution may be applied, respectively, for 2 GHz to 3 GHz, 3 GHz to 4 GHz and 4 GHz to 6 GHz.

#### Step 4: Power drift measurement

The Power Drift Measurement measures the field at the same location as the most recent power reference measurement within the same procedure, and with the same settings. The Power Drift Measurement gives the field difference in dB from the reading conducted within the last Power Reference Measurement. This allows a user to monitor the power drift of the device under test within a batch process. The measurement procedure is the same as Step 1.

#### Step 5: Z-Scan (FCC only)

The Z Scan measures points along a vertical straight line. The line runs along the Z-axis of a one-dimensional grid. In order to get a reasonable extrapolation the extrapolated distance should not be larger than the step size in Z-direction.

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## 5.3. Test Equipment

The measuring equipment used to perform the tests documented in this report has been calibrated in accordance with the manufacturers' recommendations, and is traceable to recognized national standards.

#### **Dielectric Property Measurements**

Name of Equipment	Manufacturer	Type/Model	Serial No.	Cal. Due Date
Network Analyzer	Agilent	E5071C	MY46522054	8-6-2022
Dielectric Assessment Kit	SPEAG	DAK-3.5	1196	7-21-2022
Shorting block	SPEAG	DAK-3.5 Short	SM DAK 200 BA	N/A
Thermometer	LKM	DTM3000	3851	8-4-2022
System Check				
Name of Equipment	Manufacturer	Type/Model	Serial No.	Cal. Due Date
MXG Analog Signal Generator	Agilent	N5181A	MY50145882	8-4-2022
Power Sensor	Agilent	U2000A	MY54260007	8-4-2022
Power Sensor	Agilent	U2000A	MY60180020	8-4-2022
Power Amplifier	EXODUS	1410025-AMP2027-10003	10003	8-4-2022
Directional Coupler	Agilent	772D	MY52180193	8-3-2022
Directional Coupler	Agilent	778D	MY52180432	8-3-2022
Low Pass Filter	MINI-CIRCUITS	NLP-1200	VUU19301915	8-4-2022
Low Pass Filter	MICROLAB	LA-15N	3943	8-3-2022
Low Pass Filter	FILTRON	L14012FL	1410003S	8-3-2022
Attenuator	MINI-CIRCUITS	BW-N3W5+	N/A	8-4-2022
Attenuator	Agilent	8491B/003	MY39272275	8-17-2022
Attenuator	Agilent	8491B/010	MY39272011	8-4-2022
Attenuator	Agilent	8491B/020	MY39271973	8-4-2022
E-Field Probe	SPEAG	EX3DV4	7645	4-15-2022
E-Field Probe	SPEAG	EX3DV4	7330	1-26-2022
E-Field Probe	SPEAG	EX3DV4	7376	7-30-2022
Data Acquisition Electronics (SAR3)	SPEAG	DAE4	614	3-5-2022
Data Acquisition Electronics (SAR4)	SPEAG	DAE4	1591	3-26-2022
Data Acquisition Electronics (SAR5)	SPEAG	DAE4	1494	7-27-2022
System Validation Dipole	SPEAG	D750V3	1122	2-24-2022
System Validation Dipole	SPEAG	D835V2	4d194	3-20-2022
System Validation Dipole	SPEAG	D1900V2	5d199	3-19-2022
System Validation Dipole	SPEAG	D2600V2	1097	9-19-2021
Thermometer (SAR3)	Lutron	MHB-382SD	AH.50213	8-4-2022
Thermometer (SAR4)	Lutron	MHB-382SD	AJ.45903	8-3-2022
Thermometer (SAR5)	Lutron	MHB-382SD	AK.12123	8-3-2022

#### **Others**

Name of Equipment	Manufacturer	Type/Model	Serial No.	Cal. Due Date
Base Station Simulator	R&S	CMW500	169801	8-3-2022
Base Station Simulator	R & S	CMW500	169799	8-3-2022
Base Station Simulator	R & S	CMW500	169800	8-3-2022
Base Station Simulator	R & S	CMW500	169798	8-3-2022
Base Station Simulator	R & S	CMW500	169797	8-3-2022
Base Station Simulator	R & S	CMW500	150313	8-3-2022
Base Station Simulator	R & S	CMW500	150314	8-4-2022
Base Station Simulator	R&S	CMW500	162790	8-3-2022
UXM 5G Wireless Test Platform	Keysight	E7515B	MY57510596	8-6-2022

#### Note(s):

1. For System Validation Dipole, Calibration interval applied every 2 years according to referencing KDB 865664 guidance.

2. Refer to Appendix F that mentioned about justification for Extended SAR Dipole Calibrations. (for blue box items)

3. All equipments were used until Cal.Due data.

4. Cal.certificates are refer to Appendix E & F in Part.1

5. Above equipment are list of used for the SAR test in variant model..

# 6. Device Under Test (DUT) Information

# 6.1. Wireless Technologies

Wireless technologies	Frequency bands	Operating mode	Duty Cycle used for SAR testing
W-CDMA (UMTS)	Band II Band IV Band V	UMTS Rel. 99 (Voice & Data) HSDPA (Category 24) HSUPA (Category 6) DC-HSDPA (Category 24) HSPA+ (DL only)	100%
LTE	FDD Band 2 FDD Band 4 FDD Band 5 FDD Band 7 FDD Band 12 FDD Band 13 FDD Band 25 FDD Band 26 TDD Band 41 <sub>(Power Class 2 &amp; 3)</sub> FDD Band 66 FDD Band 71 TDD Band 41 <sub>(Power Class 2 &amp; 3)</sub>	QPSK 16QAM 64QAM 256QAM Rel. 15 Carrier Aggregation (2 Uplink and 6 Downlinks)	100% (FDD) 63.3% (TDD) <sub>Power Class 3</sub> 43.3% (TDD) <sub>Power Class 2</sub>
		L LTE (1xRTT-LTE)? □ Yes ⊠ No	
5G NR (Sub 6)	FDD Band n2 FDD Band n25 TDD Band n41 <sub>(Power Class 2 &amp; 3)</sub> FDD Band n66 FDD Band n71	DFT-s-ODFM: ■ π/2 BPSK, QPSK, 16QAM, 64QAM, 256QAM CP-ODFM: ■ QPSK, 16QAM, 64QAM, 256QAM	100%
Wi-Fi	2.4 GHz	802.11b 802.11g 802.11n (HT20) 802.11ax (HE20)	SISO mode : 99.4% (802.11b) MIMO mode : 96.4% (802.11g)
	5 GHz	802.11a 802.11n (HT20), 802.11n (HT40) 802.11ac (VHT20), 802.11ac (VHT40), 802.11ac (VHT80) 802.11ax (HE20), 802.11ax (HE40), 802.11ax (HE80),	SISO mode:           96.6% (802.11a)           95.8% (802.11ac VHT80)           MIMO mode:           96.7% (802.11a)           92.1% (802.11ac VHT80)
		ds 5.60 ~ 5.65 GHz? ⊠ Yes □ No	······································
Bluetooth	Does this device support Ban 2.4 GHz	d gap channel(s)? ⊠ Yes □ No Version 5.0 LE	76 7% (DHF)
DIUELUULII		VEISION D.U LE	76.7% (DH5)

#### Notes:

1. The Bluetooth protocol is considered source-based averaging. Bluetooth GFSK (DH5) was verified to have the highest duty cycle of 76.7% and was considered and used for SAR Testing.

2. Duty cycle for Wi-Fi is referenced from the DTS and UNII report.

3. This device supports LTE Uplink CA-contiguous for LTE Band 41 (PC2 & PC3).

4. NR Band SAR test were evaluated using 100% duty cycle.

5. This device supports Smart transmit feature for 3G/4G/5G NR operations.

# 6.2. Time-Averaging for SAR

This device is enabled with Qualcomm Smart Transmit algorithm to control and manage transmitting power in real time and to ensure that the time-averaged RF exposure from 3G/4G/5G NR Sub6 WWAN is compliance with FCC requirement. This part.0 report shows SAR characterization of WWAN radios for 3G/4G/5G NR Sub6. Characterization is achieved by determining *PLimit* for 3G/4G/5G NR Sub6 that correspond to the *SAR\_design\_targets* after accounting for all device design related uncertainty. The SAR Characterization is denoted as SAR Char in this report.

## 6.3. Nomenclature for Part 0 Report

Technology	Term	Description				
	Plimit	Power level that corresponds to the exposure design target (SAR_design_target) after accounting for all device design related uncertainties				
3G/4G/	Pmax	Maximum tune up output power				
5G NR Sub6	SAR_design_target	Target SAR level < FCC SAR limit after accounting for all device design related uncertainties				
	SAR Char	Table containing Plimit for all technologies and bands				

# 7. SAR Characterizations

# 7.1. SAR Design Target

*SAR\_Design\_target* is determined by ensuring that it is less than FCC SAR limit after accounting for total device designed related uncertainties specified by the manufacturer.

SAR_design_target							
SAR_design_target< SAR_regulatory_limit $\times 10^{\frac{-Total Uncertainty}{10}}$							
1g S/	AR (W/kg)						
Total Uncertainty 1.0 dB							
SAR_regulatory_limit	1.6 W/kg						
SAR_design_target	1.0 W/kg						

# 7.2. DSI and SAR Determination

This device uses different Device State Index (DSI) to configure different time averaged power levels based on certain exposure scenarios. Depending on the detection scheme implemented in the Tablet, the worst-case SAR was determined by measurements for the relevant exposure conditions for that DSI. Detailed descriptions of the detection mechanisms are included in the operational description.

The device state index (DSI) conditions used in below table represent different exposure scenarios.

Exposure Scenario (DSI = No.)	Description	KDB guide for SAR test	
Standalone exposure Without triggering sensor (DSI = 0)	<ul> <li>Proximity sensor is not triggered even if Device was touched to user's body or hands.</li> <li>Proximity sensor is not triggered due to triggering distance.</li> </ul>	KDB 616217 D04	
Standalone exposure With triggering sensor (DSI = 1)	Proximity sensor is triggered, when Device was touched to user's body or hands.	KDB 616217 D04	

## **DSI and Corresponding Exposure Scenarios**

# 7.3. SAR Char

SAR results corresponding to *P<sub>max</sub>* for each antenna/technology/band/DSI can be found in Section.7. *Plimit* is calculated by linearly scaling with the measured SAR at the *P<sub>max</sub>* to correspond to *the SAR\_ design\_target*. *Plimit* determination for each exposure scenario corresponding to *SAR\_design\_target* are shown in table.

Device State Index (DSI)	PLimit Determination Scenarios
DSI = 0	The worst-case SAR exposure is determined as maximum SAR normalized To the limit among;
	<ol> <li>Standalone SAR measured at 14 mm spacing for Rear (Main 1 Ant.)</li> <li>Standalone SAR measured at 11 mm spacing for Rear (Main 2 Ant.)</li> </ol>
DSI = 1	<ol> <li>P<sub>limit</sub> is calculated based on Standalone SAR (1-g SAR) at 0 mm for Rear (Main 1 Ant.)</li> <li>P<sub>limit</sub> is calculated based on Standalone SAR (1-g SAR) at 0 mm for Rear (Main 2 Ant.)</li> </ol>

### Notes:

For DSI = 0, *Plimit* is calculated by:

Main 1 Ant.)

*Plimit* = *Plimit* corresponding to 1g Standalone SAR evaluation at 14 mm spacing at Rear

### Main 2 Ant.)

*Plimit* = *Plimit* corresponding to 1g Standalone SAR evaluation at 11 mm spacing at Rear

		SAR Characte	erizations		
Device State Index (	DSI)	0	1		
Exposure scenari	0	Standalone SAR without triggering sensor	Pmax – (Maximum tune-up Power)	Note.	
Test Distance (mr	n)	Refet to S	ection 7.3.	(Maximum tune-up rower) (dBm)	Note.
Spatial-average		1g	1g	(ubiii)	
WWAN Bands	Antenna	PLimit	(dBm)		
WCDMA Band II	Main.2	24.8	16.5	22.5	
WCDMA Band IV	Main.2	24.7	16.0	22.5	
WCDMA Band V	Main.1	26.9	20.0	23.5	
LTE Band 7	Main.2	24.6	16.5	23.0	
LTE Band 12	Main.1	27.7	20.0	23.5	
LTE Band 13	Main.1	26.1	20.0	23.5	
LTE Band 25 / 2	Main.2	25.2	16.5	23.5	
LTE Band 26 / 5	Main.1	27.3	20.5	23.5	
LTE Band 41-Power Class 3	Main.2	24.7	15.0	22.0	1
LTE Band 41-Power Class 2	Main.2	23.9	14.9	22.4	1
LTE Band 66 / 4	Main.2	24.3	16.5	23.5	
LTE Band 71	Main.1	27.9	20.0	23.5	
NR Band n25 / n2	Main.2	24.3	16.5	23.5	
NR Band n41-Power Class 3	Main.2	26.0	15.0	23.5	
NR Band n41-Power Class 2	Main.2	27.2	15.0	26.0	
NR Band n66	Main.2	24.2	16.5	23.5	
NR Band n71	Main.1	28.6	20.0	23.5	

### Notes:

1. All PLimit EFS and maximum tune up output Pmax levels entered in above Table correspond to average power levels after accounting for duty cycle in the case of LTE TDD modulation schemes.

2. If *Plimit* is higher than *Pmax* for some modes / bands, The modes/bands will operate at a power level up to *Pmax*.

3. P<sub>max</sub> (Maximum tune-up power) is specified in tune-up document. The maximum allowed power is equal to maximum tune up power + 1 dB device design uncertainty.

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# 8. SAR Test results for *P*<sub>limit</sub> calculations

### Standalone exposure without triggering proximity sensor (DSI = 0)

### Test results were refer to reference model (FCC ID : A3LNP545XLA).

RF Exposure Conditions	Antenna	band	mode	DSI	Test position	Test distance (mm)	Channel	Measured Output power (dbm)	measured SAR 1g (W/kg)	Plimit (dBm)
Standalone	Main 2 Ant.	WCDMA Band II	Rel.99	0	Rear	11	9400	22.9	0.647	24.8
Standalone	Main 2 Ant.	WCDMA Band IV	Rel.99	0	Rear	11	1413	22.9	0.668	24.7
Standalone	Main 1 Ant.	WCDMA Band V	Rel.99	0	Rear	14	4183	24.0	0.509	26.9
Standalone	Main 2 Ant.	LTE Band 7	QPSK BW=20MHz	0	Rear	11	21100	23.4	0.766	24.6
Standalone	Main 1 Ant.	LTE Band 12	QPSK BW=10MHz	0	Rear	14	23095	23.8	0.406	27.7
Standalone	Main 1 Ant.	LTE Band 13	QPSK BW=10MHz	0	Rear	14	23230	23.6	0.561	26.1
Standalone	Main 2 Ant.	LTE Band 66	QPSK BW=20MHz	0	Rear	11	132072	23.8	0.883	24.3
Standalone	Main 2 Ant.	NR Band n66	DFT-s-OFDM QPSK BW=20MHz	0	Rear	11	344000	23.6	0.879	24.2

#### Measured Results.(FCC ID : A3LNP545XLA1).

RF Exposure Conditions	Antenna	band	mode	DSI	Test position	Test distance (mm)	Channel	Measured Output power (dbm)	measured SAR 1g (W/kg)	Plimit (dBm)
Standalone	Main 2 Ant.	LTE Band 25	QPSK BW=20MHz	0	Rear	11	26590	24.1	0.781	25.2
Standalone	Main 1 Ant.	LTE Band 26	QPSK BW=15MHz	0	Rear	14	26865	23.7	0.440	27.3
Standalone	Main 2 Ant.	LTE Band 41-PC3	QPSK BW=20MHz	0	Rear	11	41490	23.9	0.528	26.7
Standalone	Main 2 Ant.	LTE Band 41-PC2	QPSK BW=20MHz	0	Rear	11	41055	25.5	0.595	27.8
Standalone	Main 1 Ant.	LTE Band 71	QPSK BW=20MHz	0	Rear	14	133297	23.4	0.356	27.9
Standalone	Main 2 Ant.	NR Band n25	DFT-s-OFDM QPSK BW=20MHz	0	Rear	11	372000	23.7	0.870	24.3
Standalone	Main 2 Ant.	NR Band n41-PC3	DFT-s-OFDM QPSK BW=100MHz	0	Rear	11	518598	24.2	0.659	26.0
Standalone	Main 2 Ant.	NR Band n41-PC2	DFT-s-OFDM QPSK BW=100MHz	0	Rear	11	518598	26.2	0.793	27.2
Standalone	Main 1 Ant.	NR Band n71	DFT-s-OFDM QPSK BW=20MHz	0	Rear	14	136100	23.8	0.334	28.6

#### Notes:

1. The maximum allowed power is equal to maximum tune up power + 1 dB device design uncertainty

2. Measured Output power refer to Sec.9 in SAR part.1 report.

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### Standalone exposure with triggering proximity sensor (DSI = 1)

#### Test results were refer to reference model (FCC ID : A3LNP545XLA).

RF Exposure Conditions	Antenna	band	mode	DSI	Test position	Test distance (mm)	Channel	Measured Output power (dbm)	measured SAR 1g (W/kg)	Plimit (dBm)
Standalone	Main 2 Ant.	WCDMA Band II	Rel.99	1	Rear	0	9400	17.0	0.951	17.2
Standalone	Main 2 Ant.	WCDMA Band IV	Rel.99	1	Rear	0	1413	16.5	0.822	17.4
Standalone	Main 1 Ant.	WCDMA Band V	Rel.99	1	Rear	0	4183	20.4	0.620	22.5
Standalone	Main 2 Ant.	LTE Band 7	QPSK BW=20MHz	1	Rear	0	21100	16.8	0.927	17.1
Standalone	Main 1 Ant.	LTE Band 12	QPSK BW=10MHz	1	Rear	0	23095	20.3	0.506	23.3
Standalone	Main 1 Ant.	LTE Band 13	QPSK BW=10MHz	1	Rear	0	23230	19.9	0.637	21.9
Standalone	Main 2 Ant.	LTE Band 66	QPSK BW=20MHz	1	Rear	0	132072	16.7	0.789	17.7
Standalone	Main 2 Ant.	NR Band n66	DFT-s-OFDM QPSK BW=20MHz	1	Rear	0	344000	17.0	0.784	18.1

#### Measured Results.(FCC ID : A3LNP545XLA1).

RF Exposure Conditions	Antenna	band	mode	DSI	Test position	Test distance (mm)	Channel	Measured Output power (dbm)	measured SAR 1g (W/kg)	Plimit (dBm)
Standalone	Main 2 Ant.	LTE Band 25	QPSK BW=20MHz	1	Rear	0	26590	17.1	0.980	17.2
Standalone	Main 1 Ant.	LTE Band 26	QPSK BW=15MHz	1	Rear	0	26865	20.7	0.740	22.0
Standalone	Main 2 Ant.	LTE Band 41-PC3	QPSK BW=20MHz	1	Rear	0	41490	17.6	0.729	19.0
Standalone	Main 2 Ant.	LTE Band 41-PC2	QPSK BW=20MHz	1	Rear	0	40620	18.5	0.721	19.9
Standalone	Main 1 Ant.	LTE Band 71	QPSK BW=20MHz	1	Rear	0	133297	20.0	0.839	20.8
Standalone	Main 2 Ant.	NR Band n25	DFT-s-OFDM QPSK BW=20MHz	1	Rear	0	372000	17.2	0.996	17.2
Standalone	Main 2 Ant.	NR Band n41 (PC3 & PC2)	DFT-s-OFDM QPSK BW=100MHz	1	Rear	0	518598	15.0	0.923	15.3
Standalone	Main 1 Ant.	NR Band n71	DFT-s-OFDM QPSK BW=20MHz	1	Rear	0	136100	20.6	0.782	21.7

#### Notes:

- 1. The maximum allowed power is equal to maximum tune up power + 1 dB device design uncertainty
- 2. Measured Output power refer to Sec.9 in SAR part.1 report.
- 3. Some bands were determined more conservative Plimit instead of calculation Plimit.

## **END OF REPORT**

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